

Search Notes

Application/Control No.

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Examiner

Charles Kim

Applicant(s)/Patent under
Reexamination

LEE, MI-SUEN

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

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Interference Search Report		5/26/2006	CK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
348/154,155,169; 382/103,107,173,199-text search (see search history report)	5/26/2006	CK
IEEE text search (see IEEE search report)	5/26/2006	CK